

<b>Notice of References Cited</b>	Application/Control No. 09/972,229	Applicant(s)/Patent Under Reexamination WEE ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-6,532,265	03-2003	Van der Auwera et al.	375/240.16
	C	US-6,055,316 A	04-2000	Perlman et al.	380/262
	D	US-			
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